

# Preliminary Agenda

ETS<sup>2</sup> – Emerging Test Strategies

May 27, 2014

*Chairs: Rene Segers (ReSeCo, NL), Matteo Sonza-Reorda (Politecnico di Torino, I), Stefan Eichenberger (NXP, D)*

ETS<sup>2</sup> is a new initiative to be held for the first time during ETS2014. The ETS<sup>2</sup> sessions are characterized by an industrial focus and by flexibility and informality. Consequently, the agenda as listed below is subject to change. During the actual day there may be a switch from one topic to another, and back, depending on the discussions. Also the order of the listed presentations may change, even on the fly.

The main goal is to have a lively discussion on the topics, on the presentations. The ETS<sup>2</sup> should act as a podium to discuss both problems as well as potential solutions, in order to motivate all involved, industry and academia, to move forward in the broad area of Test.

## **11.00-12.30 ETS<sup>2</sup> – Part I**

Automotive (Test) Experiences and Requirements in NXP

*Robert van Rijsinge (NXP)*

The Importance of Reliable Data

*Andre van de Geijn (Salland Engineering)*

Testing for Yield Learning, THE added value of Test

*Thomas Hermann (GLOBALFOUNDRIES)*

DPCV – Direct Probe Product Characterization Vehicle Applications, Methodology and Benefits

*Bala Murugan, Meindert Lunenburg (PDF Solutions, USA)*

## **12.30-14.00 Lunch**

## **14.00-15.30 ETS<sup>2</sup> – Part II**

Telecom (Test) Requirements and Experiences in Huawei

*Xinli Gu (Huawei)*

Analog DfT & Test, Experiences and Outlook in AMD

*Jeff Rearick (AMD)*

Analog DfT & Test, Experiences and Outlook, pov from an EDA company

*Steve Sunter (Mentor Graphics)*

Analog DfT & Test : Implementing analog Iddq

*Pete Sarson (AMS)*

## **15.30-16.15 Coffee Break**

## **16.15-17.45 ETS<sup>2</sup> – Part III**

*Chairs: Rene Segers (ReSeCo, NL), Matteo Sonza-Reorda (Politecnico di Torino, I)*

Analog DfT/Test Experiences in Freescale

*Helmut Lang (Freescale)*

NFF, *No Failures Found*, How to Learn from them

*Artur Jutman (Testonica)*

A New Way to Catch Defects that Escape Production Test but Show Up in SLT or as RMA

*Harry Chen (Mediatek)*

Operational Test Business in Europe

*Frederic Mauron (Aptasic)*

## **17.45-18.00 Closure**